

Electron microscopy – Data sheet

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Name

Group

Contact (mail)

Shortname

MW (m/v)

Date of synthesis

Batch

Structural formula

Characterisation (Spectroscopy, DLS, AFM, LM etc.)

Microscopic measurements (leave blank for operators)

Date of handover:

Desired TEM technique

- | | |
|--|--|
| <input type="checkbox"/> Cryo-TEM | <input type="checkbox"/> Freeze-Etching |
| <input type="checkbox"/> Negative staining | <input type="checkbox"/> Shadowing |
| <input type="checkbox"/> Cryo-negativ staining | <input type="checkbox"/> High-Resolution |
| <input type="checkbox"/> Image processing | <input type="checkbox"/> Else |

Date of sample preparation

Solvent / Concentration

Additives (buffer, salt, detergent etc.)

Expected (or known) structural features

Earlier TEM measurements (technique, negative numbers)

Date:

Signature

The completely filled data sheet is a prerequisite for any TEM measurement. Each new sample requires a new form. In case of questions, please contact kai.ludwig@fzem.fu-berlin.de

Please print out double-sided